

FIG.1

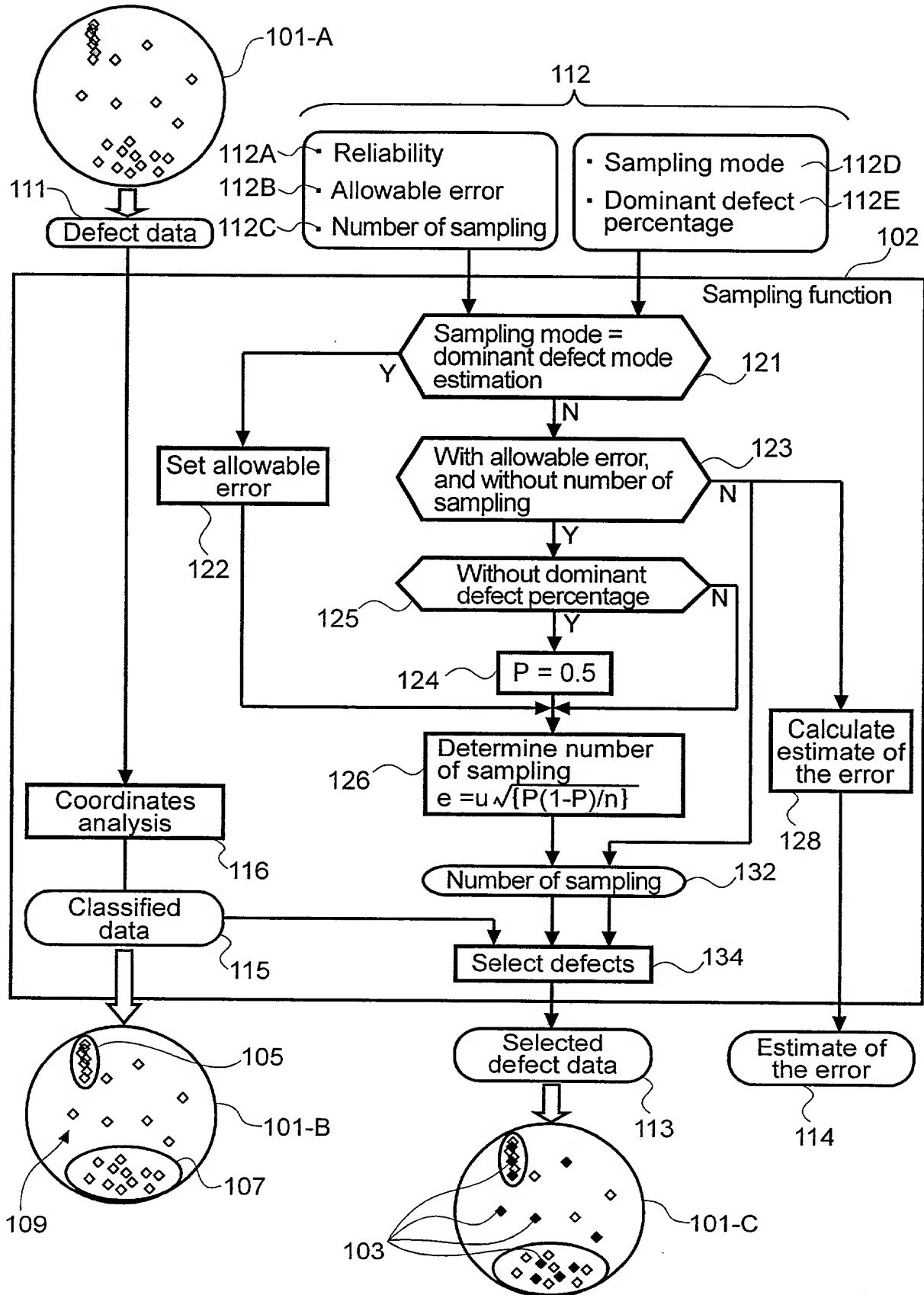


FIG.2

202

Reliability	U
0.80	1.28
0.90	1.65
0.98	2.33
...	...

FIG.3

302

326

324

322

332

336

334

U=2.33												
U=1.65												
U=1.28												
n	P											
	0.1	0.2	0.3	0.4	0.5	0.6	0.7	0.8	0.9			
	59	105	138	158	164	158	138	105	59			
	15	26	35	39	41	39	35	26	15			
e	4	7	9	10	10	10	9	7	4			
...			

FIG.4

402 {

404 {

406 {

408 {

Reliability % 442

Whole wafer 461

Classified Regions 481

High Density 482 {

Dense 484 {

Sparse 486 {

Sampling mode ▼ 462

D.D. % % 464

error % % 466

Samples Pts. 468

Pts. 469

Pts. 487

Pts. 485

Pts. 483

OK 421

CANCEL 423

FIG.5

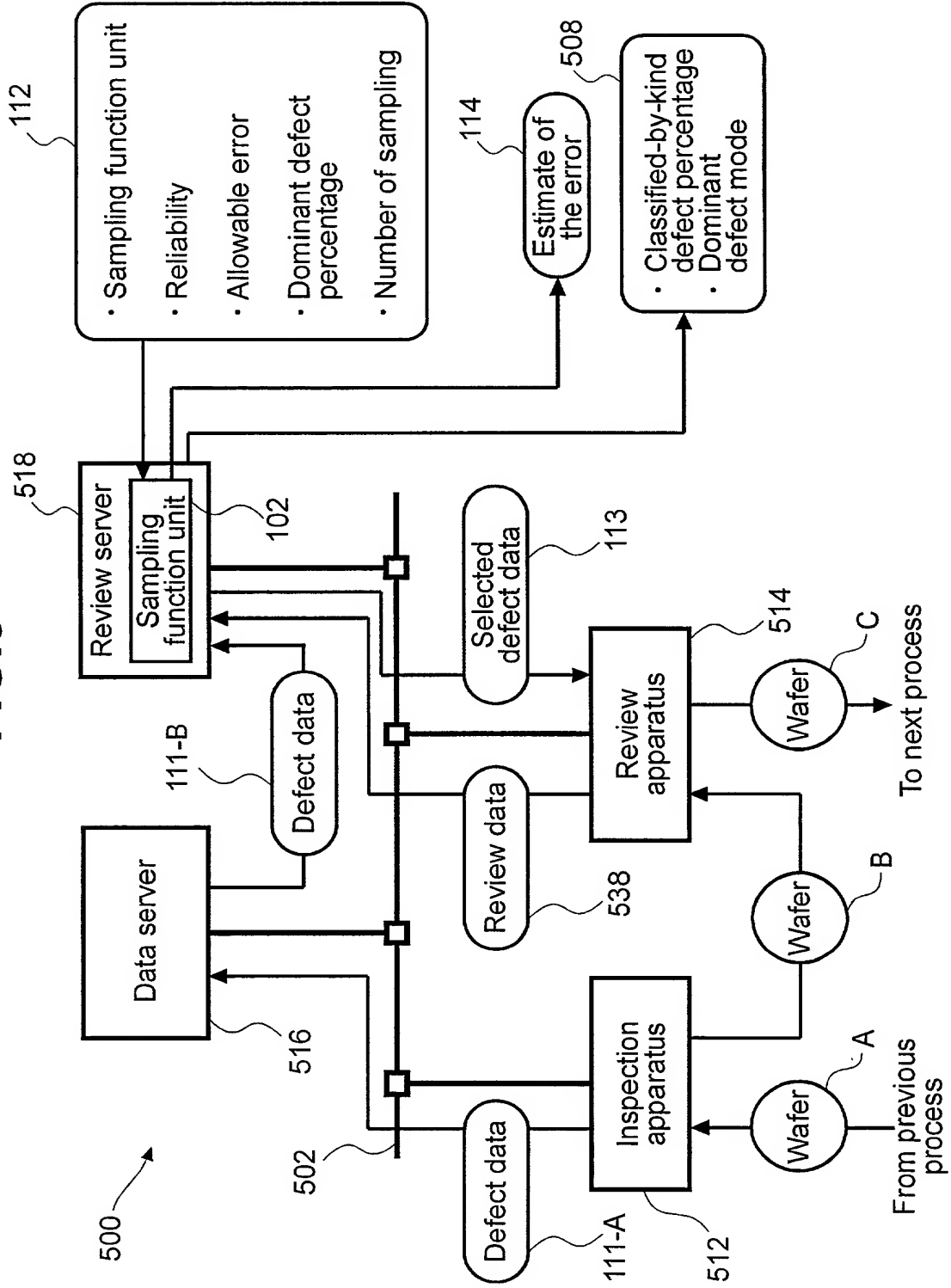


FIG.6

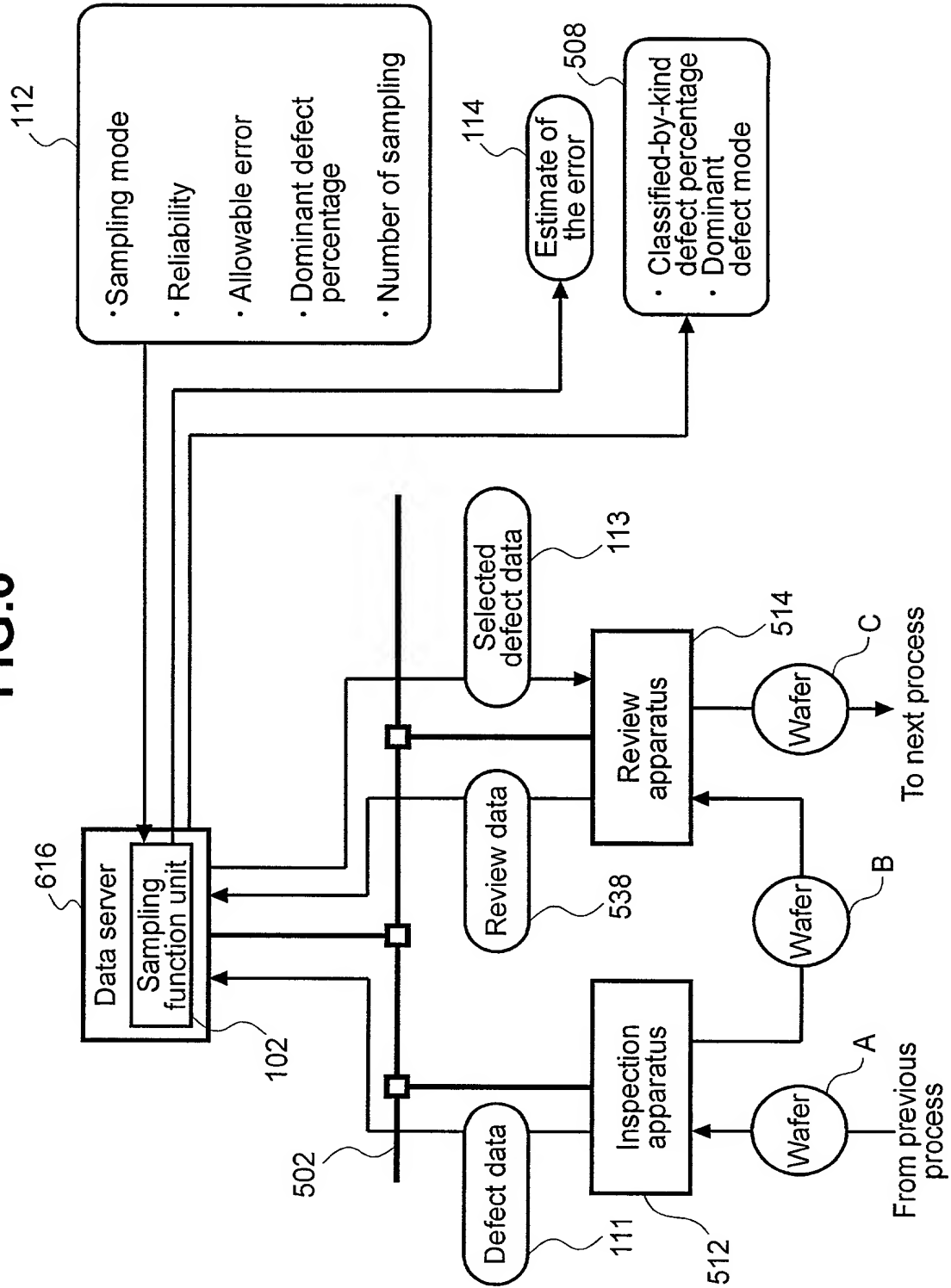
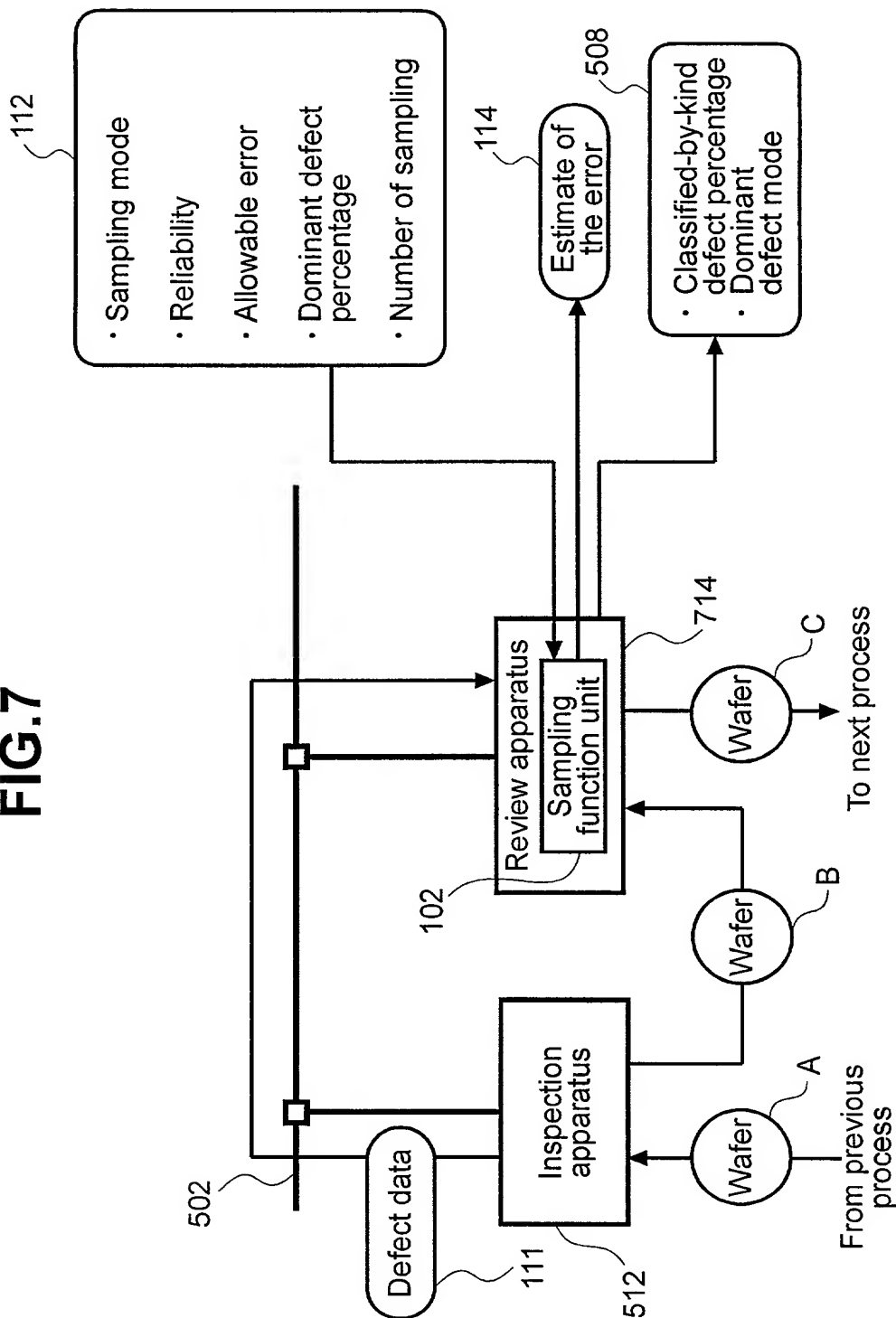


FIG. 7



112

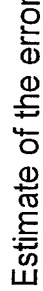


FIG. 9

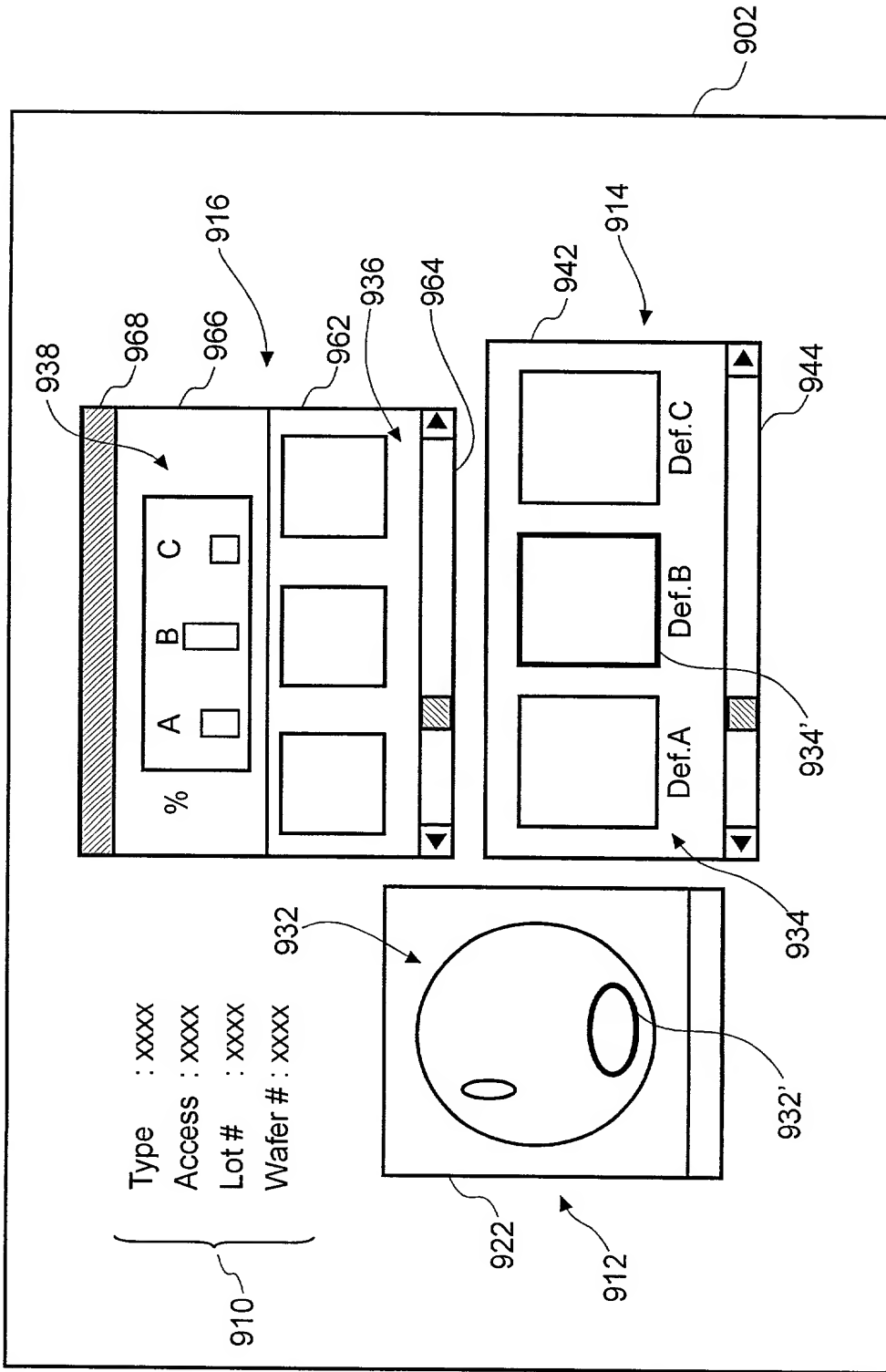
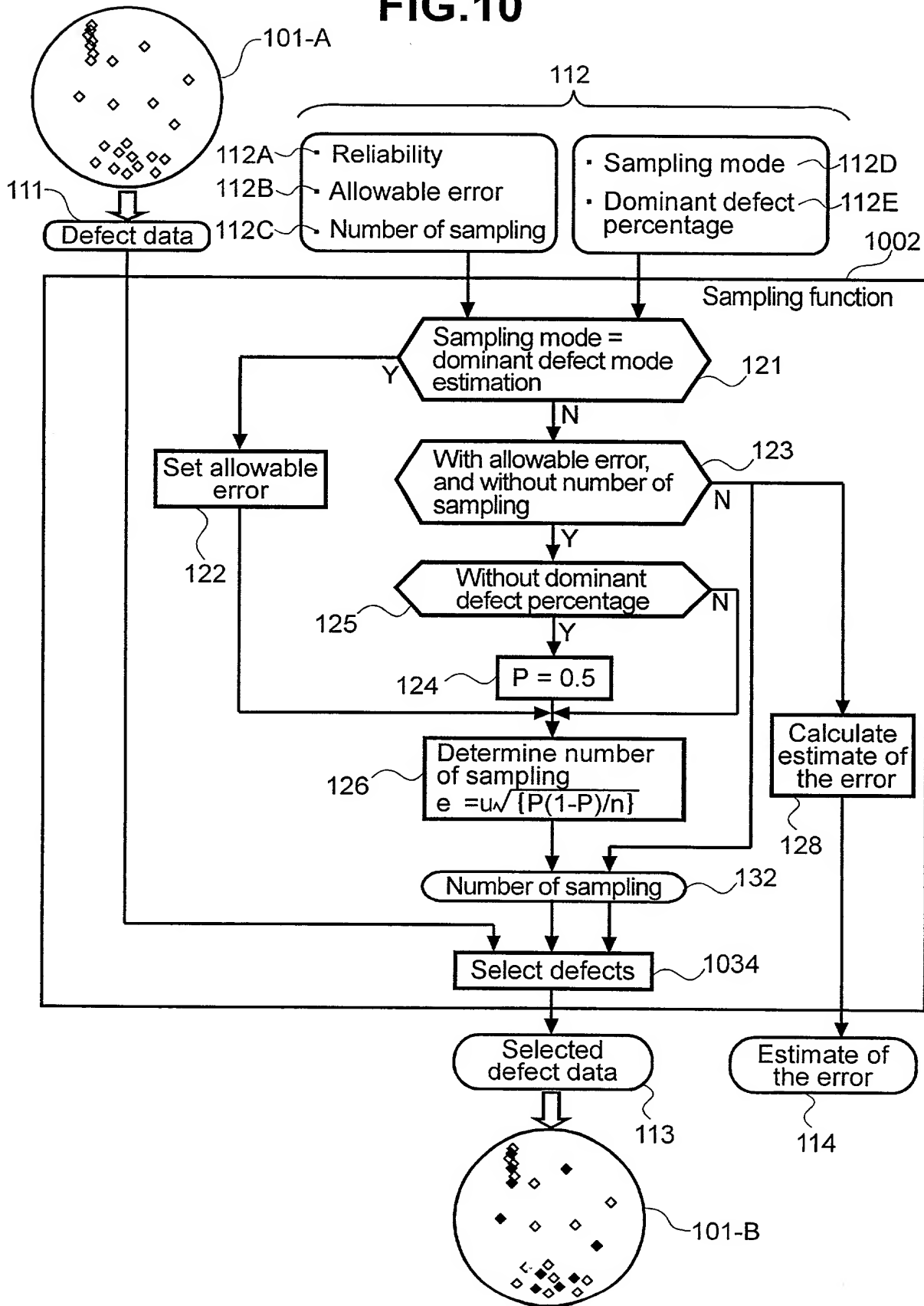


FIG.10



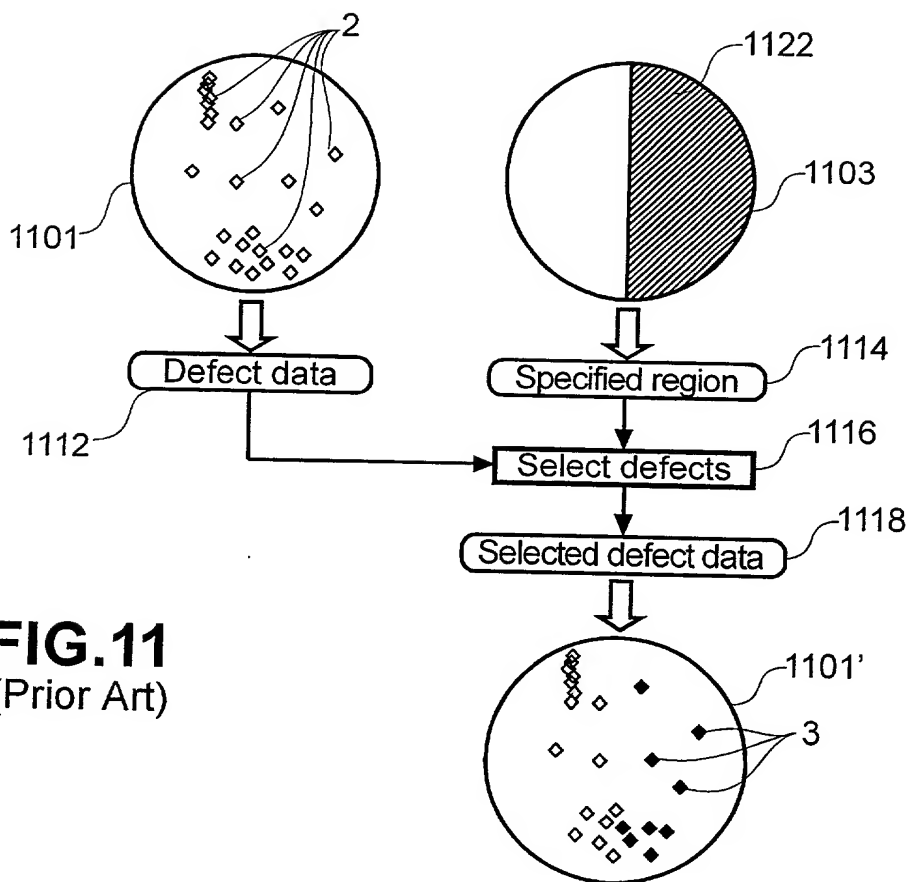


FIG. 11
 (Prior Art)

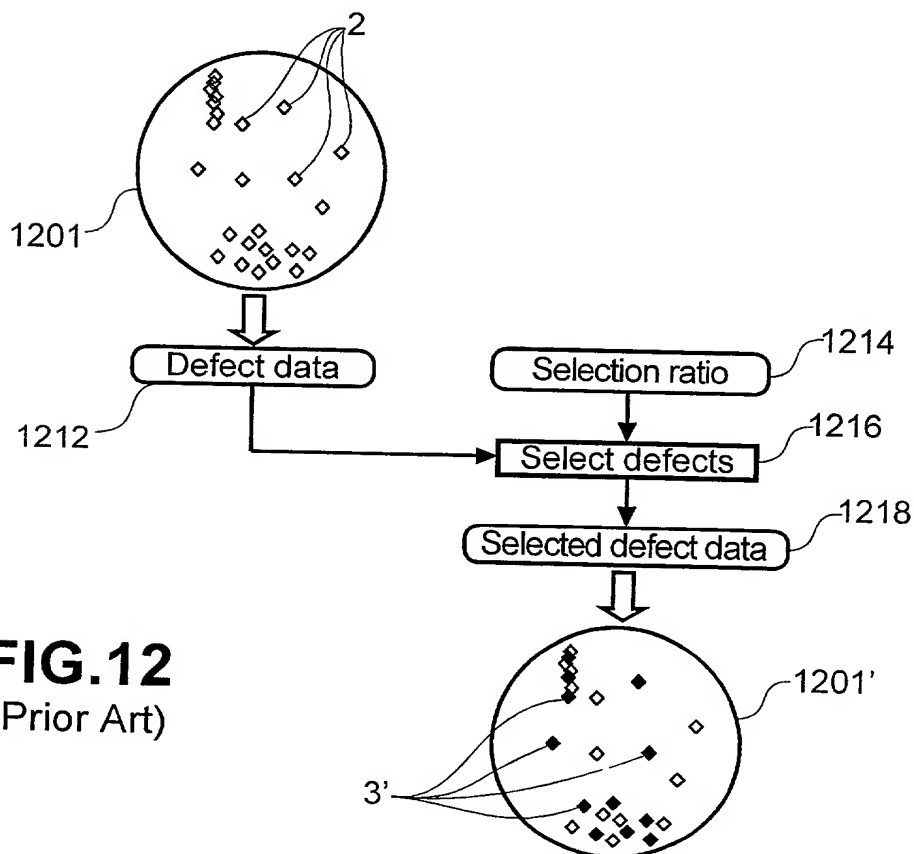


FIG. 12
 (Prior Art)